
PART NUMBER**74F534SCX-ROC**

Rochester Electronics**Manufactured Components**

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All re-creations are done with the approval of the Original Component Manufacturer. (OCM)

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceeds the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-38535
 - Class Q Military
 - Class V Space Level

Qualified Suppliers List of Distributors (QSLD)

- Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OCM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

74F534

Octal D-Type Flip-Flop with 3-STATE Outputs

General Description

The 74F534 is a high speed, low-power octal D-type flip-flop featuring separate D-type inputs for each flip-flop and 3-STATE outputs for bus-oriented applications. A buffered Clock (CP) and Output Enable ($\overline{OE}$) are common to all flip-flops. The 74F534 is the same as the 74F374 except that the outputs are inverted.

Features

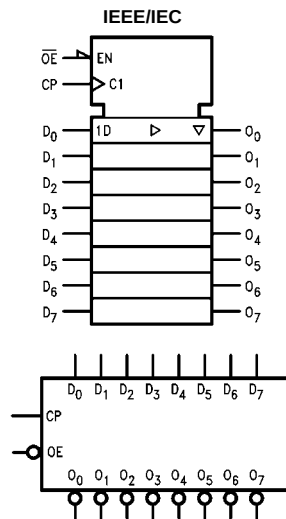
- Edge-triggered D-type inputs
- Buffered positive edge-triggered clock
- 3-STATE outputs for bus-oriented applications

Ordering Code:

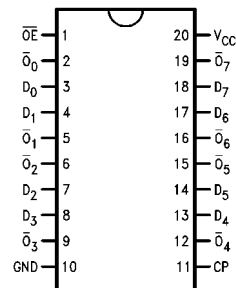
Order Number	Package Number	Package Description
74F534SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74F534SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F534PC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbols



Connection Diagram



Unit Loading/Fan Out

Pin Names	Description	U.L. HIGH/LOW	Input I_{IH}/I_{IL} Output I_{OH}/I_{OL}
D_0 – D_7	Data Inputs	1.0/1.0	20 μ A/–0.6 mA
CP	Clock Pulse Input (Active Rising Edge)	1.0/1.0	20 μ A/–0.6 mA
$\overline{OE}$	3-STATE Output Enable Input (Active LOW)	1.0/1.0	20 μ A/–0.6 mA
$\overline{O}_0$ – $\overline{O}_7$	Complementary 3-STATE Outputs	150/40(33.3)	–3 mA/24 mA (20 mA)

Function Table

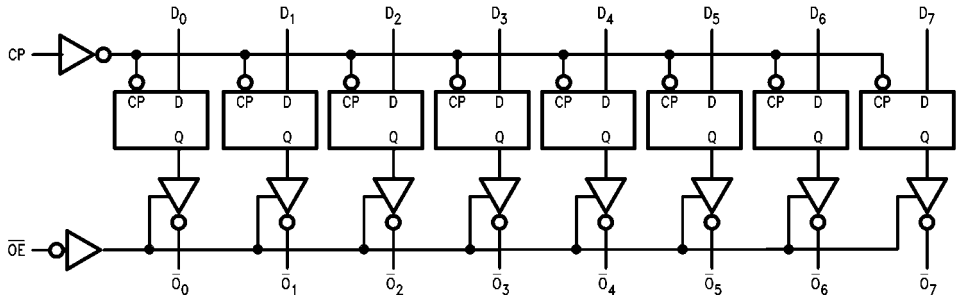
Inputs			Output
CP	$\overline{OE}$	D	$\overline{O}$
	L	H	L
	L	L	H
L	L	X	$\overline{O}_0$
X	H	X	Z

H = HIGH Voltage Level
X = Immaterial
 = LOW-to-HIGH Clock Transition
 $\overline{O}_0$ = Value stored from previous clock cycle
L = LOW Voltage Level
Z = High Impedance

Functional Description

The 74F534 consists of eight edge-triggered flip-flops with individual D-type inputs and 3-STATE complementary outputs. The buffered clock and buffered Output Enable are common to all flip-flops. The eight flip-flops will store the state of their individual D inputs that meet the setup and hold times requirements on the LOW-to-HIGH clock (CP) transition. With the Output Enable ($\overline{OE}$) LOW, the contents of the eight flip-flops are available at the outputs. When the $\overline{OE}$ is HIGH, the outputs go to the high impedance state. Operation of the $\overline{OE}$ input does not affect the state of the flip-flops.

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings(Note 1)

Storage Temperature	–65°C to +150°C
Ambient Temperature under Bias	–55°C to +125°C
Junction Temperature under Bias	–55°C to +150°C
V _{CC} Pin Potential to Ground Pin	–0.5V to +7.0V
Input Voltage (Note 2)	–0.5V to +7.0V
Input Current (Note 2)	–30 mA to +5.0 mA
Voltage Applied to Output in HIGH State (with V _{CC} = 0V)	
Standard Output	–0.5V to V _{CC}
3-STATE Output	–0.5V to +5.5V
Current Applied to Output in LOW State (Max)	twice the rated I _{OL} (mA)
ESD Last Passing Voltage (Min)	4000V

Recommended Operating Conditions

Free Air Ambient Temperature	0°C to +70°C
Supply Voltage	+4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

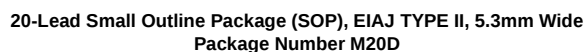
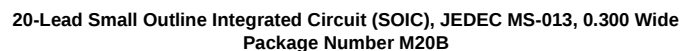
Symbol	Parameter	Min	Typ	Max	Units	V _{CC}	Conditions
V _{IH}	Input HIGH Voltage	2.0			V		Recognized as a HIGH Signal
V _{IL}	Input LOW Voltage			0.8	V		Recognized as a LOW Signal
V _{CD}	Input Clamp Diode Voltage			–1.2	V	Min	I _{IN} = –18 mA
V _{OH}	Output HIGH	10% V _{CC}	2.5		V	Min	I _{OH} = –1 mA
	Voltage	10% V _{CC}	2.4				I _{OH} = –3 mA
		5% V _{CC}	2.7				I _{OH} = –1 mA
		5% V _{CC}	2.7				I _{OH} = –3 mA
V _{OL}	Output LOW Voltage	10% V _{CC}		0.5	V	Min	I _{OL} = 24 mA
I _{IH}	Input HIGH Current			5.0	μA	Max	V _{IN} = 2.7V
I _{BVI}	Input HIGH Current Breakdown Test			7.0	μA	Max	V _{IN} = 7.0V
I _{CEX}	Output HIGH Leakage Current			50	μA	Max	V _{OUT} = V _{CC}
V _{ID}	Input Leakage Test	4.75			V	0.0	I _{ID} = 1.9 μA All Other Pins Grounded
I _{OD}	Output Leakage Circuit Current			3.75	μA	0.0	V _{IOD} = 1.50 μA All Other Pins Grounded
I _{IL}	Input LOW Current			–0.6	mA	Max	V _{IN} = 0.5V
I _{OZH}	Output Leakage Current			50	μA	Max	V _{OUT} = 2.7V
I _{OZL}	Output Leakage Current			–50	μA	Max	V _{OUT} = 0.5V
I _{OS}	Output Short-Circuit Current	–60		–150	mA	Max	V _{OUT} = 0V
I _{ZZ}	Bus Drainage Test			500	μA	0.0V	V _{OUT} = 5.25V
I _{CCZ}	Power Supply Current		55	86	mA	Max	V _O = HIGH Z

AC Electrical Characteristics

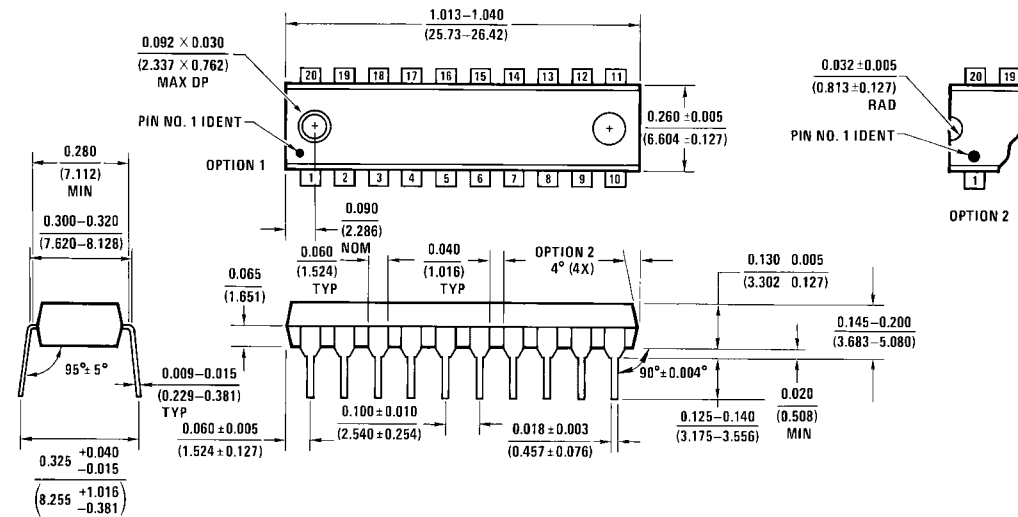
Symbol	Parameter	T _A = +25°C V _{CC} = +5.0V C _L = 50 pF			T _A = -55°C to +125°C V _{CC} = +5.0V C _L = 50 pF		T _A = 0°C to +70°C V _{CC} = +5.0V C _L = 50 pF		Units
		Min	Typ	Max	Min	Max	Min	Max	
f _{MAX}	Maximum Clock Frequency	100			60		70		MHz
t _{PLH}	Propagation Delay	4.0	6.5	8.5	4.0	10.5	4.0	10.0	ns
t _{PHL}	CP to $\overline{O_n}$	4.0	6.5	8.5	4.0	11.0	4.0	10.0	
t _{PZH}	Output Enable Time	2.0	9.0	11.5	2.0	14.0	2.0	12.5	ns
t _{PZL}		2.0	5.8	7.5	2.0	10.0	2.0	8.5	
t _{PHZ}	Output Disable Time	1.5	5.3	7.0	1.5	8.0	1.5	8.0	
t _{PLZ}		1.5	4.3	5.5	1.5	7.5	1.5	6.5	

AC Operating Requirements

Symbol	Parameter	T _A = +25°C V _{CC} = +5.0V		T _A = -55°C to +125°C V _{CC} = +5.0V		T _A = 0°C to +70°C V _{CC} = +5.0V		Units
		Min	Max	Min	Max	Min	Max	
t _S (H)	Setup Time, HIGH or LOW	2.0		2.0		2.0		ns
t _S (L)	D _n to CP	2.0		2.5		2.0		
t _H (H)	Hold Time, HIGH or LOW	2.0		2.0		2.0		
t _H (L)	D _n to CP	2.0		2.5		2.0		ns
t _W (H)	CP Pulse Width	7.0		7.0		7.0		
t _W (L)	HIGH or LOW	6.0		6.0		6.0		



Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



N20A (REV G)

20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide
Package Number N20A

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